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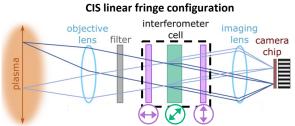
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Scrape-off layer ion temperature measurements using coherence imaging spectroscopy on the W7-X stellarator

Coherence imaging spectroscopy

Coherence imaging spectroscopy (CIS) is an optical technique that uses a polarization interferometer to obtain 2D images of plasma parameters

Compared to dispersive spectroscopy, CIS has higher optical throughput and gives more spatial information, at the cost of reduced spectral information



Spectroscopic information is encoded into a fringe

pattern having a linear spatial carrier (straight fringes)

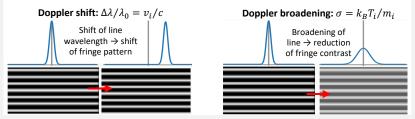
Filter isolates light from a single spectral line First polarizer linearly polarizes input light

Birefringent crystal

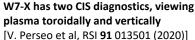
imparts a wavelengthdependent phase delay

Second polarizer acts as an analyzer, converting the phase delay into an intensity modulation

CIS viewing geometry

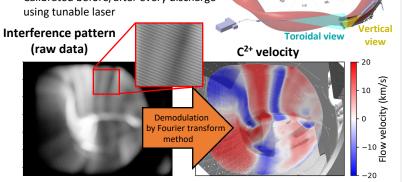


CIS diagnostic on W7-X



~1 cm spatial resolution

- ~50 ms time resolution
- Calibrated before/after every discharge using tunable laser



Accounting for Zeeman splitting in T_i analysis

Major challenge measuring scrape-off layer (SOL) T_i on W7-X: Zeeman splitting and Doppler broadening have comparable effect on linewidth

- SOL T_i in range of 10's of electron-volts
- Magnetic field varies 2.2–2.9 T throughout plasma
- Measuring T_i requires Zeeman splitting to be modelled or independently measured

CIS contrast given by $\zeta = \zeta_I \zeta_D \zeta_{MZ} \zeta_B$

- ζ₁: instrument contrast (calibration factor, ≈0.6–0.9)
- ζ_D : Doppler contrast,
- $\zeta_D = \exp\left[-k_B T_i (2\pi \widehat{N})^2 / 2m_i c^2\right]$
- ζ_{MZ}: Contrast due to multiplet and Zeeman effects
- ζ_R: Contrast due to background light (e.g. bremsstrahlung or divertor thermal emission)

C III line at 465 nm -Fit, B = 0 T, T, = 10 eV, θ = 110° Doppler broadening Fit. B = 2.2 T. T. = 10 eV. θ = 110° Doppler broadening + Zeeman splitting

Zeeman contrast calculated along every CIS line of sight (LOS)

- Magnetic field B is generated by coils \rightarrow known with high accuracy throughout plasma
- Zeeman splitting calculated along CIS lines of sight \rightarrow gives ζ_{MZ} along lines of sight

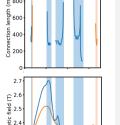
 $I_{m,z}$: intensity of multiplet/Zeeman component $v_{m,z}$: frequency of multiplet/Zeeman component \widehat{N} : interferometer group delay

Example CIS lines of sight (3D scene)



(projected onto image)

Example CIS lines of sight

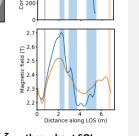


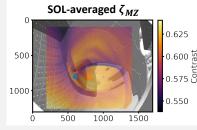
Magnetic quantities

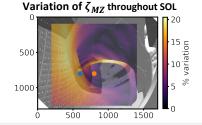
along lines of sight

Connection length is used to determine regions along lines of sight where emission can come from • L_c is infinite \rightarrow confined plasma \rightarrow no emission

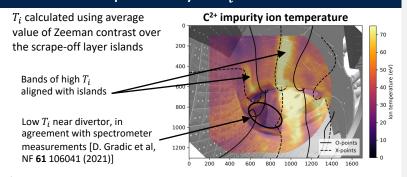
- L_c is finite \rightarrow scrape-off layer plasma \rightarrow emission possible
- Most lines of sight pass through two SOL regions (orange) example), some pass through many (blue example)







Initial scrape-off layer T_i measurements



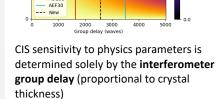
 C^{2+} temperature measurements are spuriously large: $T_i = 30-100$ eV, while other measurements show $T_e = 10-40 \text{ eV}$

→ possibly error due to Zeeman contrast variation or unaccounted for line-broadening mechanisms (bremsstrahlung, line-of-sight integration effects, spectral contamination)

Interferometer crystals optimized for measuring T_i

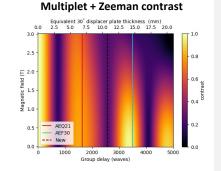
Birefringent crystals in existing two CIS instruments were optimized for **maximum contrast**, i.e., optimized for velocity measurements, not T_i \rightarrow Goal: optimize crystals for C²⁺ T_i measurements using C III line at 465 nm

Doppler contrast

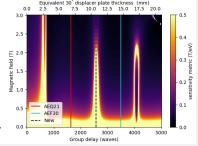


Objective: maximize sensitivity to T_i and minimize sensitivity to B

 Normalized sensitivity to T_i: $S_{T_i} = \frac{1}{\zeta_D} \frac{\partial \zeta_D}{\partial T_i} = -\frac{1}{T_C}$ (depends only on group delay)



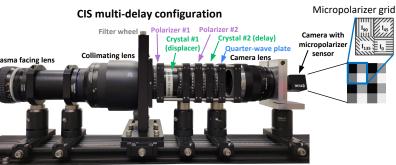
Ratio of T_i sensitivity to B sensitivity



Multi-delay CIS design

Multi-delay CIS configuration [J.S. Allcock et al, RSI 92 073506 (2021)] promises to improve T_i measurements by independently measuring B

- Standard CIS: coherence measured at one interferometer delay → limited spectral information → suitable for simple line shapes
- Multi-delay CIS: coherence measured at four interferometer delays simultaneously \rightarrow more spectral information \rightarrow can resolve more complex line shapes



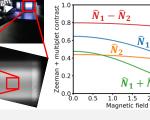
Polarizers and crystal #1 form a linear fringe pattern, encoding coherence at delay \hat{N}_1

Crystal #2, quarter-wave plate, and polarization camera form a pixelated fringe pattern, encoding coherence at delay \widehat{N}_2

Two fringe patterns are multiplied together, resulting in combined linear + pixelated fringe patterns encoding coherence at delays $\hat{N}_1 + \hat{N}_2$ and $\hat{N}_1 - \hat{N}_2$

Multi-delay CIS instrument tested on Magnetized Dusty Plasma Experiment (MDPX) [E. Thomas et al, JPP 81 (2015)] (>3 T) plasma source to

· Low-temperature, high field test ability to measure B via Zeeman contrast Analysis ongoing



redicted contrast for each delay

Conclusions

- Analysis procedure developed to account for the effect of Zeeman splitting on CIS T_i measurements in the 3D island scrape-off layer magnetic topology of W7-X
- Initial SOL T_i measurements with flow-optimized CIS diagnostic show quite high T_i bands that may be unphysical, motivating development of a new T_i -optimized instrument
- Crystals optimized for maximum ratio of T_i sensitivity to magnetic field sensitivity have been designed and procured
- Multi-delay configuration is being pursued for T_i -optimized CIS diagnostic
- Tested on MDPX and will be used for next W7-X run campaign



